PCN Number:		20170822001					PCI	N Date:	Aug 24 2017		
Titl	Title: Qualification of alternate Bond Wire Material (Au) for the TMP411EDGKR/T						Г				
Customer Contact: PCN Mana			N Manag	<u>er</u>	Dept:	Quality Services					
Proposed 1 st Ship Date: Nov 24			24 20	017	Estimated Sample Date provided at			•			
				01/	Availability: sample request			ole request			
Change Type:											
	Assembly Site			Design							
	Assembly Process				Data Sheet			Wafer Bump Material			
	Assembly Materials					mber chang	е			p Process	
L <u>L</u>	Mechanical SpecificationPacking/Shipping/Labeling				Test Site				Wafer Fab Site		
	Packir	ng/Shipp	oing/Lab	eling		Test Pr	Test Process			Wafer Fab Materials	
							Wafer Fab Process			Process	
						PCN	Details				
Des	scriptio	on of C	hange:								
	Texas Instruments is pleased to announce the qualification of Gold as an alternate bond wire for the TMP411EDGKR/T.										
	What Bond Wire Composition		an /Diam	/Diamatar C		urrent	A / 1	New Au/1.0 mils or Cu/1.0 mils			
Bond Wire Composition/Diameter				I Cu/	/1.0 mils Au/1.0 mils or Cu/1.0 mils						
Rea	Reason for Change:							Au/J	0 mi		1.0 mils
Continuity of Supply							1.0 11113	Au/1	0 mi		1.0 mils
	tinuity		-				1.0 11113	Au/ I	mi		1.0 mils
Ant	,	of Supp	bly	⁻ orm, F	it, Fu		Quality or				
Ant Non	icipate	of Supp	bly	Form, F	it, Fu						
Non	i cipat o e	of Supp ed impa	oly act on F				Quality or I				
Non	icipato e icipato No Im	of Supp ed impa	act on F act on M act on M	Aateria	I Decl ateria roduct elease	nction, aration I Declara ion data . Upon	Quality or	Reliabili oduct Cor available elease th	i ty (p entent r e follo	reports are wing the p	negative): e driven from production
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Qualification Report

TMP411EDGK Au wire Qual Approve Date 18-Jul-2017

Product Attributes

Attributes	Qual Device: TMP411EDGK	QBS Product Reference: TMP431ADGK	QBS Process/ Package Reference: INA301A1QDGKQ1	QBS Process/ Package Reference: INA301A2QDGKQ1	QBS Process/ Package Reference: INA301A3QDGKQ1
Assembly Site	ASE SHANGHAI	HNT	ASE SHANGHAI	ASE SHANGHAI	ASE SHANGHAI
Package Family	VSSOP	VSSOP	VSSOP	VSSOP	VSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	AIZU	AIZU	AIZU	AIZU	AIZU
Wafer Process	50HPA07	50HPA07	50HPA07	50HPA07	50HPA07

- QBS: Qual By Similarity

- Qual Device TMP411EDGK is qualified at LEVEL2-260C

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TMP411EDGK	QBS Product Reference: TMP431ADGK	QBS Process/ Package Reference: INA301A1QDGKQ1	QBS Process/ Package Reference: INA301A1QDGKQ1	QBS Process/ Package Reference: INA301A1QDGKQ1
HTOL	Life Test, 150C	300 Hours	-	2/154/0	1/77/0	1/77/0	1/77/0
HAST	Biased HAST 130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	1/77/0
AC	Autoclave 121C	96 Hours	-	-	1/77/0	1/77/0	1/77/0
тс	Temperature Cycle, -65/150C	500 Cycles	-	-	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake, 150C		-	-	1/45/0	-	-
HBM	ESD - HBM	4000V	1/3/0	-	-	-	-
CDM	ESD - CDM	1000V	1/3/0	-	-	-	-
LU	Latch-up	(per JESD78)	1/6/0	-	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	1/Pass	-	-	-	-

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 The following are equivalent HTOL options based on activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240Hours
 The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240Hours
 The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/100 Cycles and -65C/150C/500 Cycles
 Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com